## **EXPEDITED PROCEDURE - EXAMINING GROUP 2117**

S/N 10/612,293

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Daniel A. Day Examiner: Phung M. Chung

 Serial No.:
 10/612,293
 Group Art Unit: 2117

 Filed:
 June 30, 2003
 Docket No.: 884.879US1

Title: Selective Control of Test-Access Ports in Integrated Circuits

Customer Number: 21186

## **AMENDMENT & RESPONSE UNDER 37 C.F.R. 1.116**

Mail Stop AF Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

In response to the Final Office Action mailed May 1, 2007, please amend the application as follows: